

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Makoto KUROSAWA et al. Group Art Unit : 2831
Appln. No. : 10/597,415 Examiner : Nguyen, Hoai-An D
(U.S. National Stage of PCT/JP2005/000933)
I.A. Filed : January 19, 2005 Confirmation No. : 1744
For : PHASE MEASUREMENT DEVICE, METHOD, PROGRAM, AND
RECORDING MEDIUM

COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE

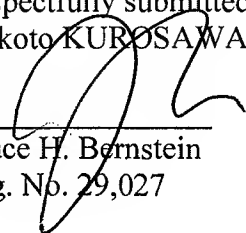
Commissioner for Patents
U.S. Patent and Trademark Office
Customer Service Window, Mail Stop Issue Fee
Randolph Building
401 Dulany Street
Alexandria VA 22314

Sir:

In response to the Notice of Allowability, mailed by the U.S. Patent and Trademark Office on September 22, 2008 and to the Statement of Reasons for Allowance attached thereto, Applicants wish to clarify the record with respect to the basis for the patentability of claims in the present application. In this regard, while Applicants do not disagree with the Examiner's indication of allowability, Applicants submit that each of the claims in the present application recite a combination of features, and that the basis for patentability of each of these claims is based on the combination of features recited therein.

Should there be any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully submitted,
Makoto KUROSAWA et al.



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November 3, 2008
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